

FCC ID:	A3LSMF936U
Date:	06/18/2022
Test Procedure:	KDB 680106 D01 v03r01

		10% Battery	50% Battery	70% Battery	
Load	E Measurements (V/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (V/m)
		15	15	15	
	A (Bottom)	0.300	0.300	0.300	614.00
	B (Right)	0.300	0.316	0.316	614.00
Phone	C (Top)	0.264	0.282	0.300	614.00
Phone	D (Left)	0.207	0.241	0.180	614.00
	E (Front)	0.362	0.362	0.362	614.00
	F (Back)	0.362	0.371	0.380	614.00

Table 1. E-field Measurement by battery level (phone load) – OPEN

Load	E Measurements (V/m)	Distance from probe (cm)	Limit (V/m)
		15	
Watch	F (Back)	1.690	614.00
Earbuds	F (Back)	2.240	614.00

Table 2. E-field Measurement by battery level (non-phone loads) – OPEN

		10% Battery	50% Battery	70% Battery	
Load	E Measurements (V/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (V/m)
		15	15	15	
	A (Bottom)	0.321	0.300	0.340	614.00
	B (Right)	0.291	0.300	0.307	614.00
Phone	C (Top)	0.272	0.291	0.300	614.00
Phone	D (Left)	0.293	0.321	0.321	614.00
	E (Front)	0.371	0.371	0.392	614.00
	F (Back)	0.496	0.496	0.538	614.00

Table 3. E-field Measurement by battery level (phone load) – CLOSED

Load	E Measurements (V/m)	Distance from probe (cm)	Limit (V/m)
		15	
Watch	F (Back)	1.617	614.00
Earbuds	F (Back)	2.167	614.00

Table 4. E-field Measurement by battery level (non-phone loads) – CLOSED

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		10% Battery	50% Battery	70% Battery	
Load	H Measurements (A/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (A/m)
		15	15	15	
	A (Bottom)	0.109	0.098	0.085	1.63
	B (Right)	0.128	0.131	0.116	1.63
Phone	C (Top)	0.105	0.091	0.091	1.63
Phone	D (Left)	0.074	0.066	0.078	1.63
	E (Front)	0.131	0.128	0.131	1.63
	F (Back)	0.142	0.138	0.138	1.63

Table 5. H-field Measurement by battery level (phone load) - OPEN

Load	H Measurements (A/m)	Distance from probe (cm)	Limit (A/m)
		15	
Watch	F (Back)	0.146	1.63
Earbuds	F (Back)	0.140	1.63

Table 6. H-field Measurement by battery level (non-phone loads) - OPEN

		10% Battery	50% Battery	70% Battery	
Load	H Measurements (A/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (A/m)
		15	15	15	
	A (Bottom)	0.103	0.105	0.098	1.63
	B (Right)	0.131	0.116	0.109	1.63
Phone	C (Top)	0.105	0.091	0.105	1.63
Phone	D (Left)	0.105	0.101	0.101	1.63
	E (Front)	0.111	0.116	0.109	1.63
	F (Back)	0.138	0.134	0.138	1.63

Load	H Measurements (A/m)	Distance from probe (cm)	Limit (A/m)
	• • •	15	
Watch	F (Back)	0.162	1.63
Earbuds	F (Back)	0.141	1.63

Table 8. H-field Measurement by battery level (non-phone loads) - CLOSED

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C	D	E	F
DGE TOP EDGE	LEFT EDGE	FRONT (SCREEN)	Back
[DGE TOP EDGE LEFT EDGE FRONT (SCREEN)

Table 9. EUT Position Description

Note:

- 1. The right and left edge are determined with the EUT screen facing the user.
- 2. H-Field Measurements were found to be noise floor

Description of Test Setup

- Testing was performed with a calibrated field probe.
- Measurement was performed on each side of the EUT as described per Table 9.
- o Testing was performed at the distances and different battery level as indicated on Tables 1 through 8.
- Measurement procedure was performed per FCC Guidance.

Test Equipment

	•			our Buo	Serial Number
Narda EHP-200AC	Electronic & Magnetic Field Probe	10/5/2020	Biennial	10/5/2022	170WX60209

Table 10. Test Equipment

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